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**TRANSACTIONS ON
PHYSICS & MATH
IN ENGINEERING SCIENCE**
SERIES A: MATERIALS & TECHNOLOGY

**X-RAY
METHODS
FOR ANALYSIS
OF CONDENSED
FILMS**

VOLUME 2



National Technical University
"Kharkiv Polytechnic Institute"

X-Ray Methods For Analysis Of Condensed Films

SHORT DESCRIPTION

The monograph is devoted to X-ray methods for studying thin films. Thin films, coatings, thin-film layered systems are the basis of modern technologies of micro- and nanoelectronics, optoelectronics, X-ray optics and microscopy. The proposed monograph presents the most important results of studies of thin-film systems obtained using original X-ray methods. The monograph is recommended for teachers, graduate students and senior students of specialties related to solid state physics.

Transactions on Physics & Math in Engineering Science

Series A: Materials & Technology

Volume 2

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X-ray Methods for Analysis of Condensed Films



National Technical University
"Kharkiv Polytechnic Institute"

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